Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination CHEN ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,154,664	11-2000	Chorey et al.	455/127.3
	В	US-6,134,424	10-2000	Nishihori et al.	455/127.1
	С	US-6,215,987	04-2001	Fujita, Masanori	455/127.3
	D	US-5,831,479	11-1998	Leffel et al.	330/124D
	E	US-5,303,395	04-1994	Dayani, Oscar	455/571
	F	US-2003/0054780	03-2003	Nunogawa et al.	455/127.2
	G	US-6,678,507	01-2004	Kurokawa et al.	455/127.1
	Н	US-6,121,841	09-2000	Sakuno, Keiichi	330/285
	ı	US-5,757,235	05-1998	Fujiwara et al.	330/296
	J	US-6,127,886	10-2000	Khabbaz et al.	330/51
	K	US-5,023,569	06-1991	Raven, Gregory S.	330/51
	L	US-6,816,714	11-2004	Toncich, Stanley S.	455/115.3
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 05291842 A	11-1993	Japan	USHIKUBO, TAKAYUKI	H03F 03/21
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NON-PATENT DOCUMENTS

*	ļ	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.